

Amendments to the Specification

Please amend the Cross Reference to Related Applications as follows:

CROSS REFERENCE TO RELATED APPLICATIONS

The present application is related to ~~U.S. Patent Application Serial No. _____, Attorney Docket 2002-0711~~ U.S. Pat. No. 7,206,012, entitled "Memory Device On Optical Scanner And Apparatus And Method For Storing Characterizing Information On The Memory Device"; ~~U.S. Patent Application Serial No. _____, Attorney Docket 2003-0848~~ U.S. Pat. Pub. No. 2005-0212905, entitled "Systems For Performing Laser Beam Linearity Correction And Algorithms And Methods For Generating Linearity Correction Tables From Data Stored In An Optical Scanner"; and ~~U.S. Patent Application Serial No. _____, Attorney Docket 2003-0839~~ U.S. Pat. Pub. No. 2005-0212903, entitled "Electronic Systems And Methods For Reducing Laser Beam Process Direction Position Errors"; each of which is filed currently herewith and hereby incorporated by reference herein.

Please amend paragraph [0027] in applicants' U.S. Pat. Pub. No. 2005/0212899 as follows:

Factors affecting process direction position errors are discussed in greater detail in ~~U.S. Patent Application Serial No. _____, Attorney Docket 2003-0839~~ U.S. Pat. Pub. No. 2005-0212903, entitled "Electronic Systems And Methods For Reducing Laser Beam Process Direction Position Errors", which is already incorporated by reference herein. For example, the bow processor 20 discussed herein corresponds to the bow system and corresponding bow processor discussed therein. Likewise, the algorithms and methods for determining laser beam process direction position errors, which are set out in the present application, may be applied to ~~U.S. Patent Application Serial No. _____, Attorney Docket 2003-0839~~ U.S. Pat. Pub. No. 2005-0212903. For example, the bow profile 35 herein corresponds to the bow profile disclosed in that application.

Please amend paragraph [0038] in applicants' U.S. Pat. Pub. No. 2005/0212899 as follows:

The beam position measurements for each of the scan planes 108, 110, 112, 114 may be taken at some time during manufacturing of the apparatus and are stored in the memory device 28 or some other memory device accessible to the controller 12. An exemplary approach to measuring points along a laser beam scan path is set out in ~~U.S. Patent Application Serial No. _____, Attorney Docket 2002-0711~~ U.S. Pat. No. 7,206,012, entitled "Memory Device On Optical Scanner And Apparatus And Method For Storing Characterizing Information On The Memory Device" to the same assignee, the contents of which are already incorporated by reference herein.

Please amend paragraph [0049] in applicants' U.S. Pat. Pub. No. 2005/0212899 as follows:

Such an approach normalizes the measurement and eliminates its dependency upon a potentially varying rotational velocity of the rotating polygonal mirror. In a similar fashion, an angle A_0 is measured, which corresponds to an angular change of the rotating polygonal mirror with respect to the start-of-scan signal 136 as the laser beam corresponding to the black scan plane 114 crosses the first test point P_0 . The angles A_1 - A_{14} are similarly measured, but are recorded relative to the preceding measurement as delta mirror angles to reduce storage requirements. That is, A_1 is the change in the angle of the rotating polygonal mirror since A_0 , etc. The angles discussed herein may be measured as is set out in ~~U.S. Patent Application Serial No. _____, Attorney Docket 2002-0711~~ U.S. Pat. No. 7,206,012, entitled "Memory Device On Optical Scanner And Apparatus And Method For Storing Characterizing Information On The Memory Device" to the same assignee, the contents of which are already incorporated by reference herein.

Please amend paragraph [00130] in applicants' U.S. Pat. Pub. No. 2005/0212899 as follows:

Also, once the laser beam scan path model 32 is properly constructed, it is possible to perform any sort of scaling thereof. For example, margin adjustments, the lengthening or shortening of a line can be implemented by scaling the corresponding computed laser beam scan path model 32. It should also be noted that the velocity of the laser beam changes as it is swept in a scan direction. As such, some linearity correction may be required. Linearity correction and margin/line length corrections are set out in ~~U.S. Patent application Serial No. _____, Attorney Docket 2003-0848~~ U.S. Pat. Pub. No. 2005-0212905, entitled "Systems For Performing Laser Beam Linearity Correction And Algorithms And Methods For Generating Linearity Correction Tables From Data Stored In An Optical Scanner", which is already incorporated by reference herein.

Please amend paragraph [00159] in applicants' U.S. Pat. Pub. No. 2005/0212899 as follows:

The microprocessor 18 derives a bow profile 35 that is stored in the main system memory 16 for each Pel profile 34. The bow profiles 35 essentially translate their corresponding Pel profile 34 into a format suitable for processing by the bow processor 20. As one example, each Pel profile 34 is encoded into a corresponding bow profile 35 as part of a series of instructions, referred to generally as source address list entries. Each source address list entry encodes a portion, e.g., 64 Pel locations, of the Pel profile 34, and includes other operational data that the bow processor 20 may use during operation. The bow processor 20 and the bow profile 35, including corresponding source address list instructions executed thereby, are set out in greater detail in ~~U.S. Patent Application Serial No. _____, Attorney Docket 2003-0839~~ U.S. Pat. Pub. No. 2005-0212903, entitled "Electronic Systems And Methods For Reducing Laser Beam Process Direction Position Errors", which is already incorporated by reference herein.